

Study of photovoltaic multilayers

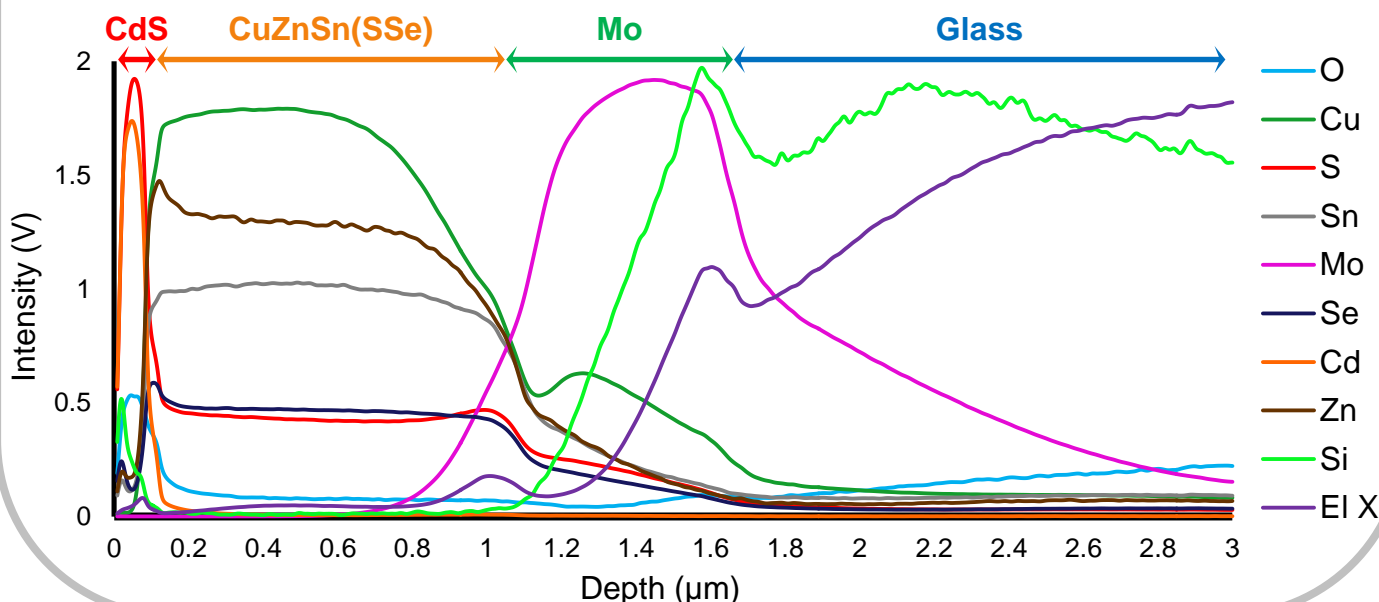
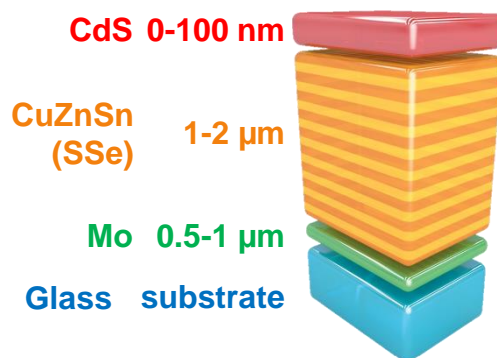
Subject: Elemental depth profiles of a multilayer used in photovoltaic application.

Technique: **GD-OES**

- ✓ Qualitative depth profiles
- ✓ Until a depth of several tens of microns
- ✓ Shape and dimensions of the sample: flat surface, diameter > 11 mm

Results:

- 3 layers (thicknesses measurements)
- Elemental composition verification
- Diffusion between the layers
- At the interfaces, diffusion of X element
- Traces detection (0 to 100ppm): C, N, Cl ...



Conclusions:

- Check of number, thickness and elemental composition of the layers
- Migration/diffusion phenomena between the layers
- Traces detection of potential pollutants